## Notice of References Cited Application/Control No. Applicant(s)/Patent Under Reexamination AMANAI, TAKAHIRO Examiner Arnel C. Lavarias Applicant(s)/Patent Under Reexamination AMANAI, TAKAHIRO Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0085517	05-2004	Togino et al.	353/031
*	В	US-5,897,192	04-1999	Seufert, Heinz	353/74
*	С	US-5,046,793	09-1991	Hockley et al.	359/12
*	D	US-6,198,554	03-2001	Kanda et al.	359/28
	E	US-			
	F	US-			
	G	US-		i .	
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003029343 A	01-2003	Japan	AMAUCHI, TAKAHIRO	G03B 21/60
	0	JP 2000284677 A	10-2000	Japan	ONO et al.	G03H 01/22
	Р					
	σ			:		
	R					•
	s					
	Т					

## NON-PATENT DOCUMENTS

NON-FAICH DOCUMENTS							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	υ	NONE					
	<b>v</b>						
	W						
	x						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.